

<b>Notice of References Cited</b>	Application/Control No. 10/583,367		Applicant(s)/Patent Under Reexamination BAILLEUL ET AL.	
	Examiner Jason D. Mitchell		Art Unit 2193	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,751,795 B1	06-2004	Nakamura, Kazuhisa	717/174
*	B	US-2005/0091642 A1	04-2005	Miller, William L.	717/124
*	C	US-2005/0076328 A1	04-2005	Berenbach et al.	717/104
*	D	US-2005/0125769 A1	06-2005	McGovern et al.	717/102
*	E	US-2005/0166178 A1	07-2005	Masticola et al.	717/104
*	F	US-7,003,534 B2	02-2006	Peng, Luosheng	707/758
*	G	US-2007/0028226 A1	02-2007	Chen et al.	717/168
*	H	US-7,472,374 B1	12-2008	Dillman et al.	717/102
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	I. Macfarlane, I. Reilly "Requirements traceability in an integrated development environment"; 1995; Proceedings of the Second IEEE International Symposium on Requirements Engineering.
	V	J. Schulz "Requirements-Based UML"; 2001; Proceedings of the 39th International Conference and Exhibition on Technology of Object-Oriented Languages and Systems.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.